

Notice of References Cited	Application/Control No. 10/581,959	Applicant(s)/Patent Under Reexamination YOON, IL SHIK	
	Examiner Stefan Kruer	Art Unit 3654	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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	N	JP 03293276 A	12-1991	Japan	ENDO, MASAHIKO	B66B 5/00
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NON-PATENT DOCUMENTS

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